

Marshall Wilson

List of Publications by Year in descending order

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Version: 2024-02-01

13
papers

160
citations

1478505

6
h-index

1588992

8
g-index

13
all docs

13
docs citations

13
times ranked

169
citing authors

#	ARTICLE	IF	CITATIONS
1	Method for noncontact measurement of 2DEG mobility and carrier density in AlGaIn/GaN on semi-insulating wafers. Japanese Journal of Applied Physics, 2022, 61, 020903.	1.5	1
2	Simple and versatile UV-ozone oxide for silicon solar cell applications. Solar Energy Materials and Solar Cells, 2018, 185, 505-510.	6.2	21
3	Recent Advancement in Charge and Photo-Assisted Non-Contact Electrical Characterization of SiC, GaN, and AlGaIn/GaN HEMT. ECS Transactions, 2017, 80, 261-274.	0.5	0
4	Review—Recent Advancement in Charge- and Photo-Assisted Non-Contact Electrical Characterization of SiC, GaN, and AlGaIn/GaN HEMT. ECS Journal of Solid State Science and Technology, 2017, 6, S3129-S3140.	1.8	11
5	Influence of surface preparation and cleaning on the passivation of boron diffused silicon surfaces for high efficiency photovoltaics. Thin Solid Films, 2017, 636, 412-418.	1.8	9
6	Improving Silicon Surface Passivation with a Silicon Oxide Layer Grown via Ozonated Deionized Water., 2017, , .		3
7	Non-Visual Defect Monitoring with Surface Voltage Mapping. ECS Journal of Solid State Science and Technology, 2016, 5, P3087-P3095.	1.8	7
8	Drift characteristics of mobile ions in SiNx films and solar cells. Solar Energy Materials and Solar Cells, 2015, 142, 102-106.	6.2	37
9	Non-Visual Defect Monitoring with Surface Voltage Mapping: Application for Semiconductor IC and PV Technology. Solid State Phenomena, 2015, 242, 472-477.	0.3	1
10	Importance of defect photoionization in silicon-rich SiN_x dielectrics for high PID resistance. , 2013, , .		8
11	Novel Noncontact Approach to Characterization of Mobility in Inversion Layers Using Corona Charging of Dielectric and SPV Monitoring of Sheet Resistance. ECS Transactions, 2010, 28, 33-41.	0.5	3
12	COCOS (corona oxide characterization of semiconductor) non-contact metrology for gate dielectrics. AIP Conference Proceedings, 2001, , .	0.4	57
13	Improved High Precision Dopant/Carrier Concentration Profiling with Corona-Charge Non-Contact C-V (CnCV). Materials Science Forum, 0, 1004, 237-242.	0.3	2